

P-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R_{DS(on)} (Ω)	I _D (A)	Q _g (Typ.)			
- 100	0.160 at V _{GS} = - 10 V	- 2.5 ^c	23.2 nC			
- 100	0.200 at V _{GS} = - 4.5 V	- 2.3 ^c	23.2 110			

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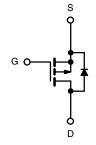
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FEATURES

- TrenchFET[®] Power MOSFET
- 100% R_g and UIS Tested

APPLICATIONS

- Active Clamp in Intermediate DC/ DC Power Supplies
- H-Bridge High Side Switch for Lighting Application



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T _A = Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		V _{DS}	- 100	V	
Gate-Source Voltage		V _{GS}	± 20		
	T _C = 25 °C		- 2.5		
Continuous Drain Current (T ₁ = 150 °C)	T _C = 70 °C		- 2.3		
Continuous Drain Current $(1_j = 150^{\circ}C)$	T _A = 25 °C	I _D	- 2 ^{a, b}		
	T _A = 70 °C		- 1.6 ^{a, b}	•	
Pulsed Drain Current	I _{DM}	- 15	A		
Continuous Courses Drain Diada Current	T _C = 25 °C		- 4.9		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 2.5 ^{a, b}		
Avalanche Current		I _{AS}	- 15		
Single-Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	11.25	mJ	
	T _C = 25 °C		5.9		
Maximum Dawar Dissinction	T _C = 70 °C		3.8	w	
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^{a, b}	vv	
	T _A = 70 °C		2 ^{a, b}		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C		

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. t = 10 s.

c. Based on T_C = 25 °C.

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, b}	t ≤ 10 s	R _{thJA}	33	40	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	17	21	0/00	

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. Maximum under steady state conditions is 80 °C/W.

AM4481P-T1-PF

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 100			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 165			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	5	-	- 6.6		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \ \mu A$	- 1		- 3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zara Cata Valtaga Drain Current	I _{DSS}	V _{DS} = - 100 V, V _{GS} = 0 V	- 1		- 1		
Zero Gate Voltage Drain Current		V_{DS} = - 100 V, V_{GS} = 0 V, T_{J} = 55 °C			- 10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -5 V$, $V_{GS} = -10 V$	- 8			А	
	D	V _{GS} = - 10 V, I _D = - 2 A		0.160			
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5V, I _D = - 1.5 A		0.200		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = 2 A		12		S	
Dynamic ^b							
Input Capacitance	C _{iss}			1190		pF	
Output Capacitance	C _{oss}	V _{DS} = - 50 V, V _{GS} = 0 V, f = 1 MHz	-	61			
Reverse Transfer Capacitance	C _{rss}		-	42			
Total Gate Charge	Qg	$V_{DS} = -50 \text{ V}, \text{ V}_{GS} = -10 \text{ V}, \text{ I}_{D} = -2 \text{ A}$		27.5	42	nC	
				23.2	35		
Gate-Source Charge	Q _{gs}	V_{DS} = - 50 V, V_{GS} = - 6 V, I_D = - 2 A	-	5.4			
Gate-Drain Charge	Q _{gd}			8.4			
Gate Resistance	R _g	f = 1 MHz		6.1	9.2	Ω	
Turn-On Delay Time	t _{d(on)}			20	30		
Rise Time	t _r	V_{DD} = - 75 V, R_L = 25 Ω		95	145		
Turn-Off DelayTime	t _{d(off)}	${ m I}_{ m D}\cong$ - 3 A, ${ m V}_{ m GEN}$ = - 6 V, ${ m R}_{ m g}$ = 1 Ω		38	60		
Fall Time	t _f			34	51		
Turn-On Delay Time	t _{d(on)}			11	18	ns	
Rise Time	t _r	V_{DD} = - 75 V, R_L = 25 Ω		28	42		
Turn-Off DelayTime	t _{d(off)}	$\text{I}_\text{D}\cong$ - 2 A, V_GEN = - 10 V, R_g = 1 Ω		52	78		
Fall Time	t _f			35	53		
Drain-Source Body Diode Characterist	ics						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			- 13	^	
Pulse Diode Forward Current ^a	I _{SM}				- 15	A	
Body Diode Voltage	V _{SD}	I _S = - 2 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			65	90	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = - 4 A, dl/dt = 100 A/μs, T _J = 25 °C		180	270	nC	
Reverse Recovery Fall Time	t _a			45			
Reverse Recovery Rise Time	t _b			20		ns	

Notes:

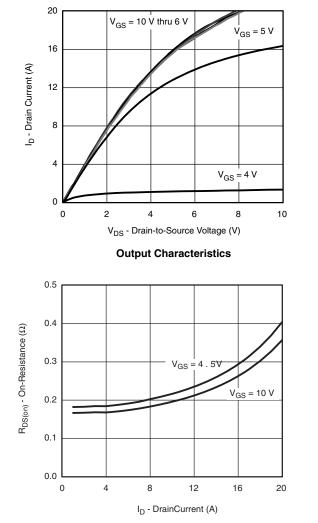
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

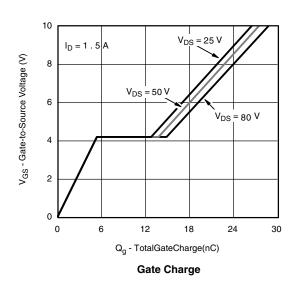
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

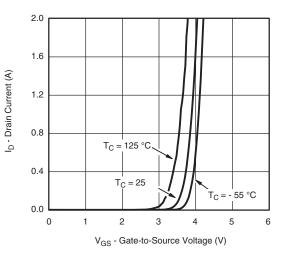
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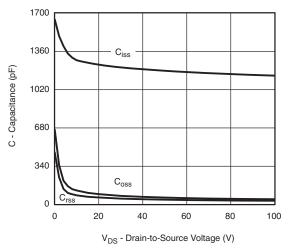


On-Resistance vs. Drain Current and Gate Voltage

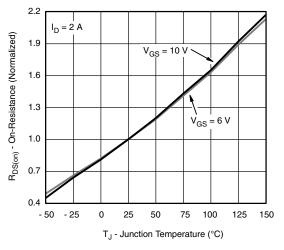




Transfer Characteristics

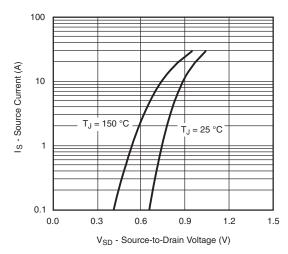


Capacitance

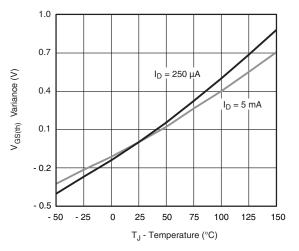


On-Resistance vs. Junction Temperature

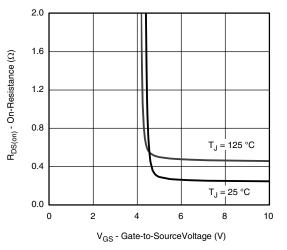




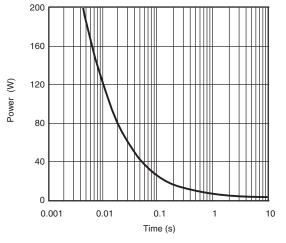
Source-Drain Diode Forward Voltage



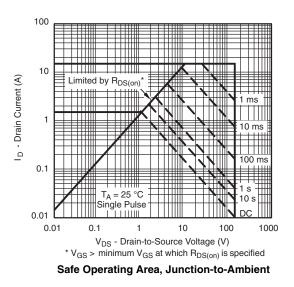
Threshold Voltage



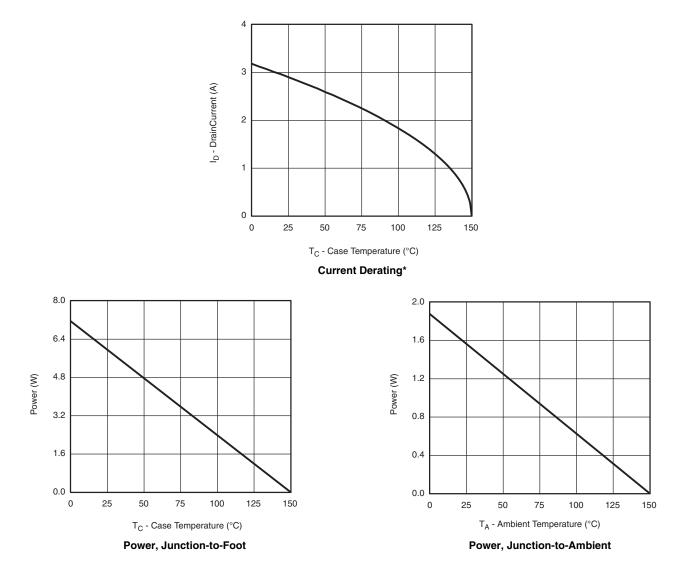
On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power, Junction-to-Ambient

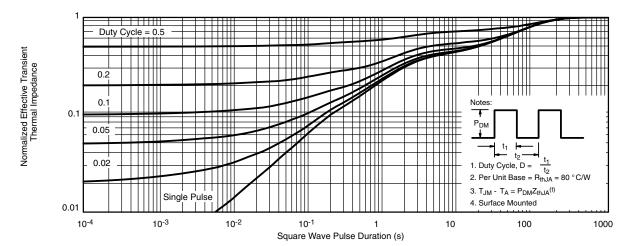




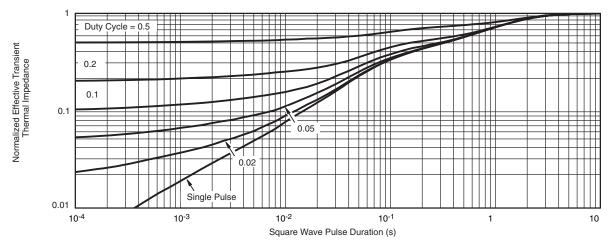


* The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

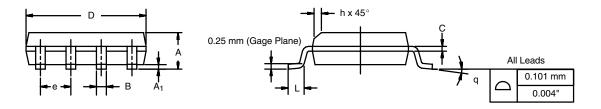


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012





	MILLIM	IETERS	INC	HES	
DIM	Min	Мах	Min	Max	
A	1.35	1.75	0.053	0.069	
A ₁	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
ECN: C-06527-Rev. I, 11-Sep-06 DWG: 5498					



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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